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(71) Applicant (for all designated States except US): **ICT INTEGRATED CIRCUIT TESTING GESELLSCHAFT FÜR HALBLEITERPRÜFTECHNIK MBH [DE/DE];**
Ammerthalstrasse 20a, 85551 Heimstetten (DE).

(72) Inventors; and

(75) Inventors/Applicants (for US only): **FEUERBAUM, Hans-Peter [DE/DE];** Arno-Assmann-Strasse 14, 81739 Munich (DE). **FROSSEN, Juergen [DE/DE];** Kufsteinerstrasse 16a, 85521 Riemerling (DE). **HOFFMANN,**

Ull [DE/DE]; Forststrasse 39a, 85521 Riemerling (DE). **WINKLER, Dieter [DE/DE];** Stademannstrasse 6, 81737 Munich (DE). **ADAMEC, Pavel [CZ/DE];** Jagdfeldring 25, 85540 Haar (DE).

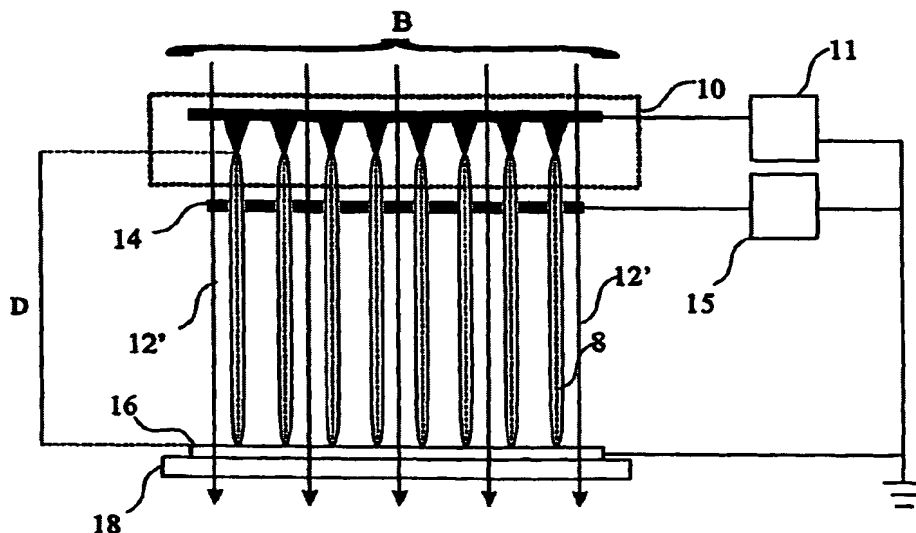
(74) Agents: **GINZEL, Christian et al.; Zimmermann & Partner, P.O. Box 330 920, 80069 Munich (DE).**

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(54) Title: **IMAGING SYSTEM WITH MULTI-SOURCE ARRAY**



(57) Abstract: The present invention provides a charged particle beam device. The device comprises an emitter array (22) for emitting a plurality of charged particle beams (8). The plurality of charged particle beams are imaged with a lens (12). An electrode unit (14) is provided for accelerating the plurality of charged particle beams. The potential differences between a first potential of the emitter array, a second potential of the electrode unit, and a third potential of a specimen, are controlled by a first control unit (11) and a second control unit. Thereby, the second potential is capable of accelerating the plurality of charged particle beams with respect to the first potential, and the third potential is capable of decelerating the plurality of charged particle beams with respect to the second potential.

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